

**Search Notes**

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Examiner

Chuck Huynh

Applicant(s)/Patent under  
Reexamination

JUNG ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
Updated	Search	11/25/2006	HT
455	566	11/25/2006	HT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/subclass	11/25/2006	HT
Citations and Combined text search	11/20/2006	HT